

WAN Tester II



- Tests asynchronous, synchronous, DDS T-1, fractional T-1, E-1 and fractional E-1, E-1, T-3 and E-3 facilities and equipment
- V.35, RS232, RS422/RS530, X.21, HSSI, DDS, T-1, E-1, T-3 and E-3 interfaces
- Data rates from 50 bps to 50 Mbps
- Built-in speaker for monitoring DS0s or timeslots
- Displays G.821 performance measurements
- Front Panel, Windows GUI or terminal Command Line Interface
- AC and battery power

The Telinc WAN Tester II is a sophisticated bit error rate tester in a compact, hand held package. It can test a wide variety of communications facilities and equipment including DDS, T-1, fractional T-1, E-1, fractional E-1, T-3 and E-3 NTUs, multiplexers, CSU/DSUs, T-1 CSUs, DTUs and TIUs. It includes a speaker to listen to voice in a DS0. It is supplied with changeable nickel metal hydride batteries and a built-in charger.

T-1 and E-1 Testing

In the T-1 and E-1 modes, the Tester displays bit errors, transmit and receive frequency, test seconds, bit error rate and G.821 performance measurements (errored seconds, severely errored seconds, degraded minutes and available and unavailable times). A variety of test patterns can be inserted in all or selected DS0s/timeslots, continuous or non-contiguous, making the Tester ideal for fractional T-1 or E-1 testing. In the T-1 mode, it also displays RX level in db and volts.

T-3 and E-3 Testing

The WAN Tester II can test T-3 and E-3 networks and CSUs. It performs G.821 measurements and displays bit errors, bit error rate, frequency and more.

Async and Sync Testing

In the async and sync modes, the WAN Tester generates test data in a choice of patterns and formats. The user can choose from a selection of twenty-eight async and seventy-five sync test speeds. The Tester counts and displays bit errors, bit error rate, and total test seconds. In the asynchronous mode, it also counts and displays characters received, character errors and errored seconds. In the synchronous mode, it also displays transmit frequency, receive frequency, clear to send delay and G.821 performance measurements.

DDS Testing

The Tester also includes a DDS analyzer. It can operate at speeds from 2400 to 72,000 bps in normal and Secondary Channel modes. It can simulate a CSU/DSU to test networks or a network to test CSU/DSUs.

Easy to use

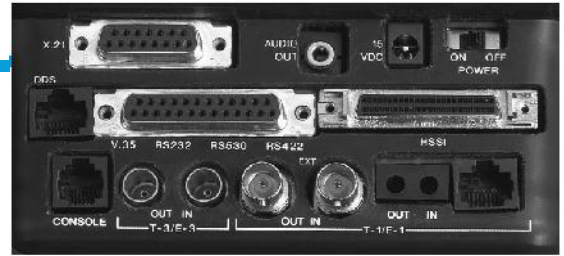
The WAN Tester I can be controlled from the front panel or from a local or remote terminal. It includes a two-line LCD display and sixteen indicator lights that show selected mode, test and operating parameters. Parameters are selected by scrolling through values stored in the Tester.

WAN Tester II

Specifications

ASYNCR

Speeds: 50 to 115,000 bps
Displays: Character Errors, Characters Received, Total Test Seconds and Errored Seconds
LEDS: Pattern Lock, Pattern Recovered, TXD, RXD, RTS, CTS, DSR, CD, and DTR
Patterns: 2⁹ (511), 2¹¹ (2047), Binary, Fox Test, Mark and Space
Loops: Self-Test
Interfaces: V.35, RS530, RS422 and RS232 Physical: DB 25 pin Female



The Telinc Tester is supplied complete with all the interfaces listed.

SYNCR

Speeds: 1,200 to 50,000,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Err'd Secs, Severely Err'd Secs, Degraded Mins, Avail, Unavail, RX Freq, TX Freq, Bits Received, RTS Time, Round Trip Delay
LEDS: Pattern Lock, Pattern Recovered, Transmit Data, Receive Data, RTS (C), CTS, DSR, CD (I), DTR, TXC, RXC (S), and External TXC
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, ITU 2¹⁵, QRSS, 2²⁰, ITU 2²⁰, 2²³, ITU 2²³, 1 of 8, 3 of 24, Alt, Mark, Space, Round Trip Delay and User 3 - 32
Loops: Self-Test and V.54
Interfaces: V.35/DB25, RS530/DB25, RS422/DB25, RS232/DB25, X.21/DB15 and HSSI/50 pin

DDSR

Speeds: 2,400 to 72,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Secondary Errors, Severely Errored Secs, Degraded Mins, Available, Unavail, RX Freq, TX Freq, Bits, RX Level dB, Simplex Current, Round Trip Delay and RLOS Secs
LEDS: Pattern Lock, Pattern Recovered, CMI (IDLE), All 1s, All 0s, RLOS, OOF, OOS, CSU Loop, DSU Loop and V.54 Loop
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, QRSS, 1 of 8, 3 of 24, Alt, Mark, Space, DDS1, DDS2, DDS3, DDS4, Round Trip Delay and User 3 - 32
Loops: Self-Test, CSU Loop, DSU Loop and V.54 Loop
Interfaces: Four wire, BiPolar Physical: RJ48S

T-1

Speed: 1,544,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Signalling Bits, Density Errs, Frame Errs, CRC Err, BPV Err, RX Level Volts & dB, Slips, Round Trip Delay
LEDS: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, D4, ESF, AMI, B8ZS and Yellow
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, ITU 2¹⁵, QRSS, 2²⁰, ITU 2²⁰, 2²³, ITU 2²³, 1 of 8, 3 of 24, T-1 DALY, T-1 DALY UF, 55 Octet, 55 Octet UF, Alt, Mark, Space, Digimwatt, User 3 - 32, Round Trip Delay, DDS OCU Loop, DDS CSU Loop and DDS DSU Loop
Loops: Self-Test, ATT Loop U/D, ANSI Loop U/D, ATT Payload, ANSI Payload, Smart Jack 1 & 2 (Framed & Unframed) and V.54
Interfaces: DS1 BiPolar, 110 Ohm, AMI/B8ZS Coding Physical: RJ48C and Dual Bantam

E-1

Speed: 2,048,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavail, RX Freq, TX Freq, CRC Errs, BPV Errs and Frame Errs
LEDS: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, ITU 2¹⁵, QRSS, 2²⁰, ITU 2²⁰, 2²³, ITU 2²³, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32
Loops: Self-Test and V.54
Interfaces: G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: Dual Bantam, Dual BNC and RJ48C

T-3

Speed: 44,736,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, P-Bit Errs, C-Bit Errs, T3 Frame Errs, LCV Err, FEBE Err, Excessive 0s and LOS Secs
LEDS: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, ITU 2¹⁵, QRSS, 2²⁰, ITU 2²⁰, 2²³, ITU 2²³, 1111, IDLE 1100, AIS 1010, 0000, 1 of 8 and User 3 - 32
Loops: Self-Test and CSU
Interfaces: DS3 BiPolar, 75 Ohm Physical: Dual Mini WECO 560A

E-3

Speed: 34,368,000 bps
Displays: Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, LCVs, LOS Secs and Frame Errs
LEDS: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, BPV, and RAI
Patterns: 2⁹ (511), 2¹¹ (2047), 2¹⁵, ITU 2¹⁵, QRSS, 2²⁰, ITU 2²⁰, 2²³, ITU 2²³, 1 of 8, Alt, Mark, Space and User 3 - 32
Loops: Self-Test and LINE
Interfaces: G.703/751, 75 Ohm, HDB3 Coding Physical: Dual Mini WECO 560A

Mechanical: The WAN Tester II measures 8.75" (22.2 cm) H x 7.5" (19.1 cm) W x 4" (10.2 cm) D and weighs 4.4 lbs (1.81 kg)

Part Numbers for ordering

TL2085B WAN Tester II

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